

SIC MOSFET CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2nd generation Silicon Carbide trench technology, the 650 V CoolSiC™ MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

Features

- Ultra-low switching losses
- Benchmark gate threshold voltage, $V_{GS(th)} = 4.5 \text{ V}$
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

Benefits

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- · Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

Potential applications

- SMPS
- Solar PV inverters
- · Energy storage and battery formation
- UPS
- EV charging infrastructure
- Motor drives

Product validation

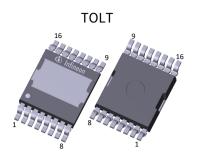
Fully qualified according to JEDEC for Industrial Applications

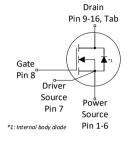
Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction.

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V
$R_{\mathrm{DS(on),typ}}$	26	mΩ
R _{DS(on),max}	33	mΩ
$Q_{G,typ}$	42	nC
$I_{\rm D,pulse}$	216	А
Q _{oss} @ 400 V	80	nC
E _{oss} @ 400 V	10.8	μЈ

Type/Ordering Code	Package	Marking	Related Links
IMLT65R026M2H	PG-HDSOP-16	65R026M2	see Appendix A







Public

CoolSiC™ MOSFET 650 V G2 IMLT65R026M2H



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1 Maximum ratings

at $T_i = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Darameter	Symphol		Value	S	Limit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Continuous DC drain current ¹⁾	I _{DDC}	-	-	82 57	А	$T_c = 25$ °C $T_c = 100$ °C
Peak drain current ²⁾	I _{DM}	-	-	216	А	$T_{\rm c}$ = 25°C, $V_{\rm GS}$ = 18 V
Avalanche energy, single pulse	E _{AS}	-	-	200	mJ	I _D = 7.5 A, V _{DD} = 50 V; see table 11
Avalanche energy, repetitive	E_{AR}	-	-	1.00	mJ	I _D = 7.5 A, V _{DD} = 50 V; see table 11
Avalanche current, single pulse	I _{AS}	-	-	7.5	А	-
MOSFET <i>dv/dt</i> ruggedness	dv/dt	-	-	200	V/ns	V _{DS} = 0400 V
Gate source voltage (static) 3)	V_{GS}	-7	-	23	V	-
Gate source voltage (transient)	V_{GS}	-10	-	25	V	t _p ≤ 500 ns, duty cycle ≤ 1%
Power dissipation	P_{tot}	-	-	365	W	T _c = 25°C
Storage temperature	$T_{\rm stg}$	-55	-	150	°C	-
Operating junction temperature	T _j	-55	-	175	°C	-
Mounting torque	-	-	-	-	Ncm	-
Continuous reverse drain current 1)	I _{SDC}	-	-	82 54	А	$V_{GS} = 18 \text{ V}, T_c = 25^{\circ}\text{C}$ $V_{GS} = 0 \text{ V}, T_c = 25^{\circ}\text{C}$
Peak reverse drain current ²⁾	I _{SM}	-	-	216 65	А	$T_c = 25^{\circ}\text{C}, t_p \le 250 \text{ ns}$ $T_c = 25^{\circ}\text{C}$
Insulation withstand voltage	V _{ISO}	-		n.a.	V	$V_{\rm rms}$, $T_{\rm c} = 25$ °C, $t = 1$ min

¹⁾ Limited by $T_{j,max}$.

Pulse width t_{pulse} limited by $T_{\text{j,max}}$.

³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



2 Thermal characteristics

Table 3 Thermal characteristics

Downwarten.	Symbol		Values			Note / Test Condition
Parameter		Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case	$R_{th(j-c)}$	-	-	0.41		Not subject to production test. Parameter verified by design/characterization according to JESD51-14.
Soldering temperature, reflow soldering allowed	$T_{\rm sold}$	-	_	260	°C	reflow MSL1



3 Operating range

Table 4 Operating range

Parameter	Symbol	,	Values			Note/ Test Condition
raiailietei	Syllibol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Recommended turn-on voltage	$V_{GS(on)}$	-	18	1	٧	-
Recommended turn-off voltage	$V_{GS(off)}$	-	0	-	V	-



4 Electrical characteristics

at $T_i = 25$ °C, unless otherwise specified

Table 5 Static characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition	
raiailletei	Syllibol	Min.	Тур.	Мах.	Oilit	Note/ Test Condition	
Drain-source voltage	$V_{ m DSS}$	650	-	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm D} = 0.7 \text{ mA}$	
Gate threshold voltage ⁴⁾	$V_{\rm GS(th)}$	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}$, $I_{\rm D} = 7$ mA	
Zero gate voltage drain current	I _{DSS}	_	1 3	75 -	μΑ	$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25^{\circ}\text{C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175^{\circ}\text{C}$	
Gate-source leakage current	$I_{\rm GSS}$	-	-	100	nA	$V_{\rm GS} = 20 \text{ V}, \ V_{\rm DS} = 0 \text{ V}$	
Drain-source on-state resistance	$R_{ m DS(on)}$	-	34 26 24 43	- 33 - -	mΩ	$V_{GS} = 15 \text{ V}, I_D = 34.5 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 18 \text{ V}, I_D = 34.5 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 20 \text{ V}, I_D = 34.5 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 18 \text{ V}, I_D = 34.5 \text{ A}, T_j = 175^{\circ}\text{C}$	
Internal gate resistance	$R_{G,int}$	-	2.9	-	Ω	f= 1 MHz	

Tested after 1 ms pulse at V_{GS} = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.

Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized. For layout recommendations please use provided application notes or contact Infineon sales office.

Parameter	Symbol	Values			Unit	Note/ Test Condition
i didilietei	Syllibot	Min.	Тур.	Мах.	Offic	Note, rest condition
Input capacitance	C _{iss}	-	1499	-	pF	$V_{\rm GS} = 0 \text{ V}, V_{\rm DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Reverse transfer capacitance	$C_{\rm rss}$	-	8.6	-	pF	$V_{\rm GS} = 0 \text{ V}, V_{\rm DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output capacitance ⁵⁾	C _{oss}	-	111	145	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output charge ⁵⁾	$Q_{\rm oss}$	-	80	103	nC	calculation based on C _{oss}
Effective output capacitance, energy related ⁶⁾	$C_{ m o(er)}$	-	135	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$
Effective output capacitance, time related ⁷⁾	$C_{ m o(tr)}$	-	199	-	pF	$I_{\rm D}$ = constant, $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 0400 V
Turn-on delay time	$t_{ m d(on)}$	-	9.3	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 34.5 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Rise time	t _r	-	10.1	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 34.5 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10



Dynamic characteristics Table 6

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized.

For layout recommendations please use provided application notes or contact Infineon sales office.

Parameter	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Turn-off delay time	$t_{\sf d(off)}$	-	16	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 34.5 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Fall time	t _f	-	5.1	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 34.5 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Turn-ON switching losses ⁸⁾	E _{on}	-	43	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V},$ $I_{\rm D} = 34.5 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$
Turn-OFF switching losses ⁸⁾	$E_{ m off}$	-	33	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V},$ $I_{\rm D} = 34.5 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$
Total switching losses ⁸⁾	$E_{ m tot}$	-	76	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V},$ $I_{\rm D} = 34.5 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$

Maximum specification is defined by calculated six sigma upper confidence bound

Table 7 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Syllibot	Min.	Тур.	Мах.	Onic	Note, rest condition
Plateau gate to source charge	$Q_{GS(pl)}$	-	11.0	-	nC	$V_{DD} = 400 \text{ V}, I_{D} = 34.5 \text{ A},$ $V_{GS} = 0 \text{ to } 18 \text{ V}$
Gate to drain charge	Q_{GD}	-	7.9	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm D} = 34.5 \text{ A},$ $V_{\rm GS} = 0 \text{ to } 18 \text{ V}$
Total gate charge	Q_{G}	-	42	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm D} = 34.5 \text{ A},$ $V_{\rm GS} = 0 \text{ to } 18 \text{ V}$

Reverse diode characteristics Table 8

Parameter	Symbol	Values			Linit	Note/ Test Condition
- arameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Drain-source reverse voltage	$V_{\rm SD}$	-	4.3	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm S} = 34.5 \text{ A}, T_{\rm j} = 25^{\circ}\text{C}$
MOSFET forward recovery time	t _{fr}	-	16 10.7	-	ns	$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 34.5 \text{A},$ $di_{\rm S}/dt = 1000 \text{A/\mu s}; \text{see table 9}$ $V_{\rm DD} = 400 \text{V}, I_{\rm S} = 34.5 \text{A},$ $di_{\rm S}/dt = 4000 \text{A/\mu s}; \text{see table 9}$

 $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.

 $C_{\rm o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 400 V.

⁸⁾ Values for 4-pin configuration based on TO-263-7 measurements; MOSFET used in half-bridge configuration without external diode



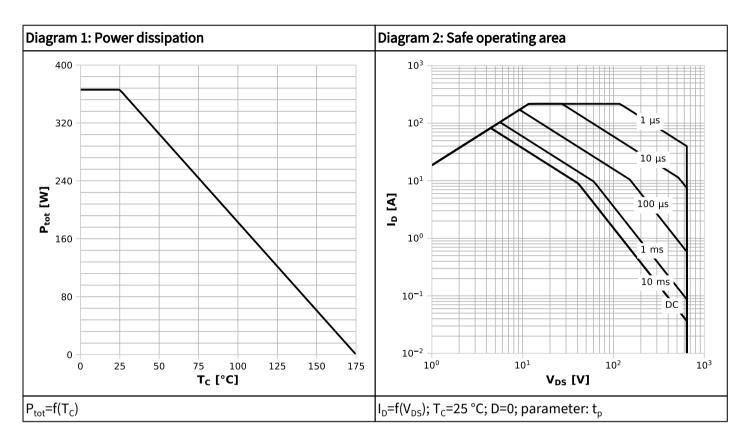
Table 8 Reverse diode characteristics

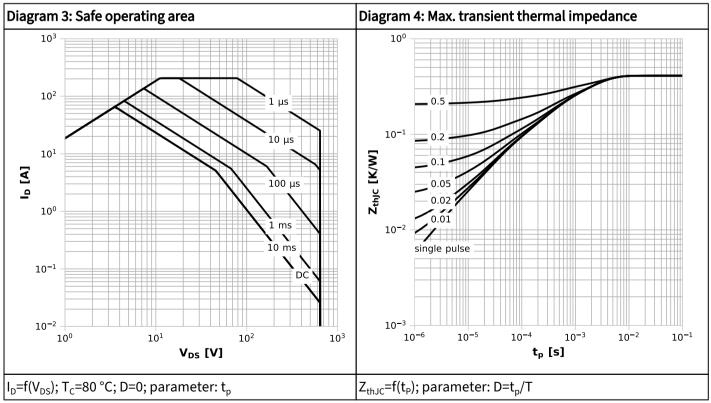
Parameter	Symbol	,	Values			Note/ Test Condition
	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Colldition
MOSFET forward recovery charge ⁹⁾	Q_{fr}	-	83 131	-	nC	$V_{DD} = 400 \text{ V}, I_{S} = 34.5 \text{ A},$ $di_{S}/dt = 1000 \text{ A}/\mu\text{s}; \text{ see table 9}$ $V_{DD} = 400 \text{ V}, I_{S} = 34.5 \text{ A},$ $di_{S}/dt = 4000 \text{ A}/\mu\text{s}; \text{ see table 9}$
MOSFET peak forward recovery current	I_{frm}	-	10.6 25	-	A	$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 34.5 \text{A},$ $di_{\rm S}/dt = 1000 \text{A/\mu s}; \text{see table 9}$ $V_{\rm DD} = 400 \text{V}, I_{\rm S} = 34.5 \text{A},$ $di_{\rm S}/dt = 4000 \text{A/\mu s}; \text{see table 9}$

⁹⁾ Q_{fr} includes Q_{oss}

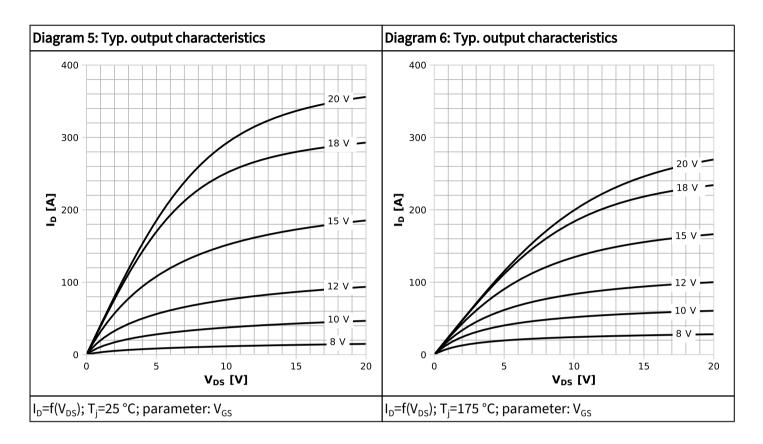


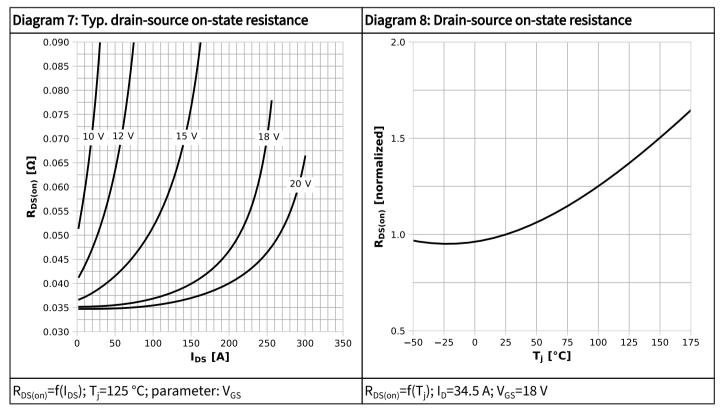
5 Electrical characteristics diagrams



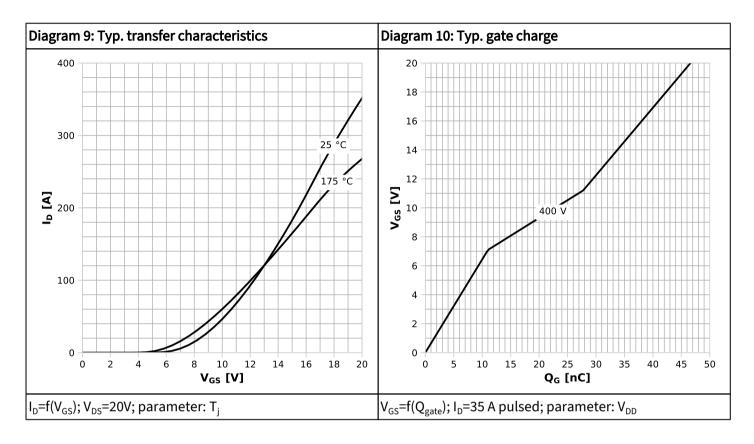


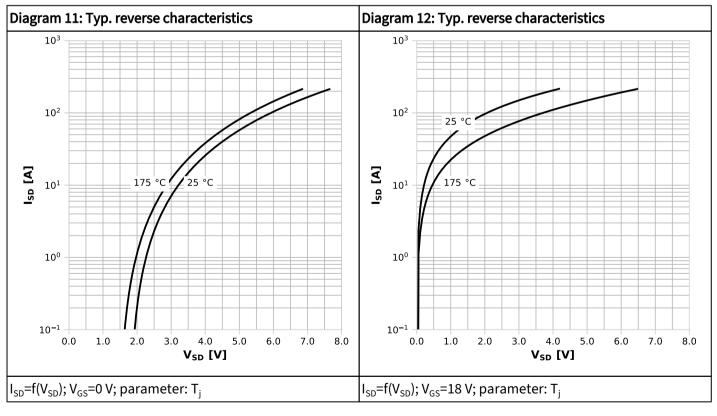




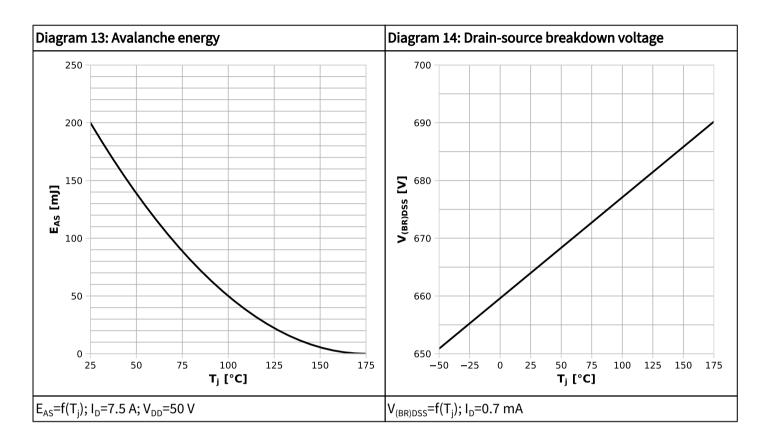


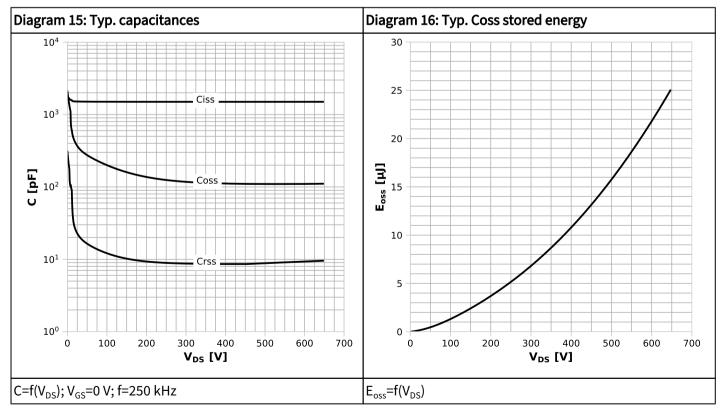




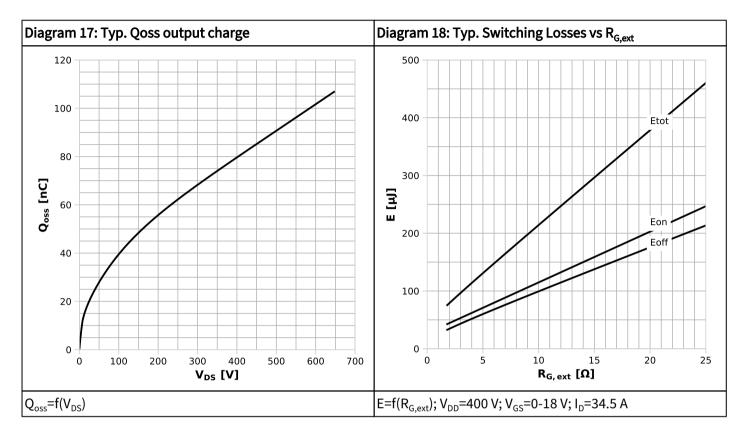


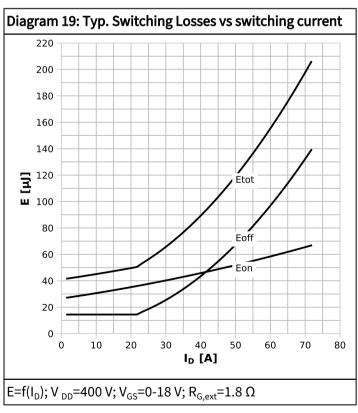














6 Test Circuits

Table 9 Body diode characteristics (CoolSiC)

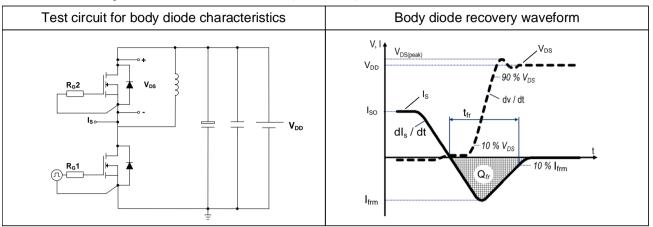


Table 10 Switching times (CoolSiC)

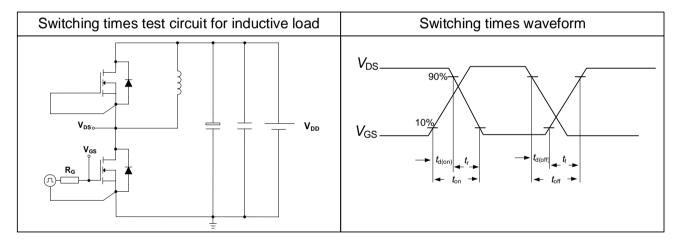


Table 11 Unclamped inductive load





7 Package Outlines

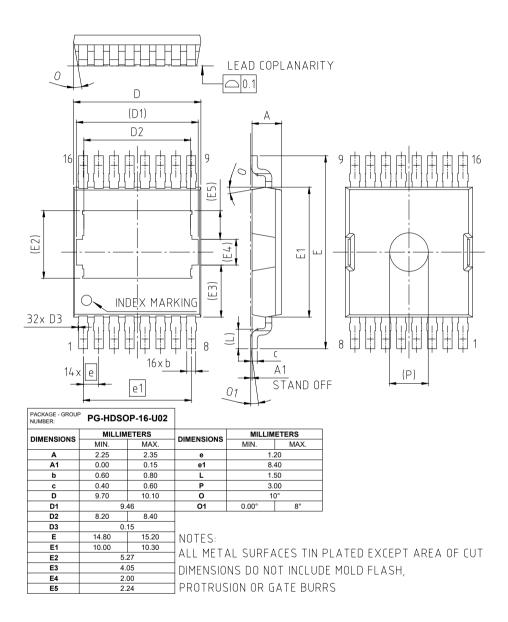


Figure 1 Outline PG-HDSOP-16, dimensions in mm



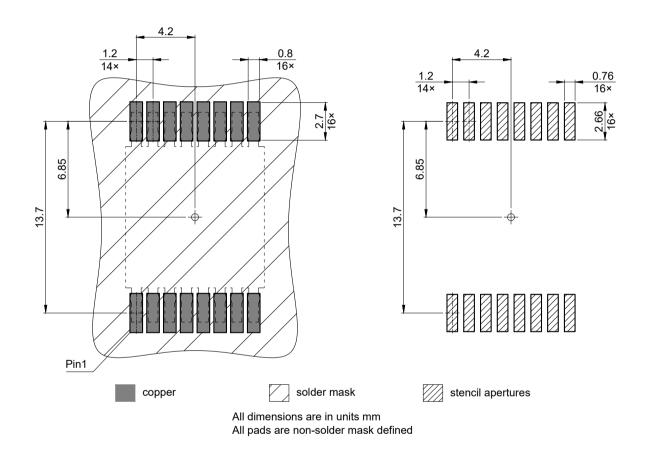
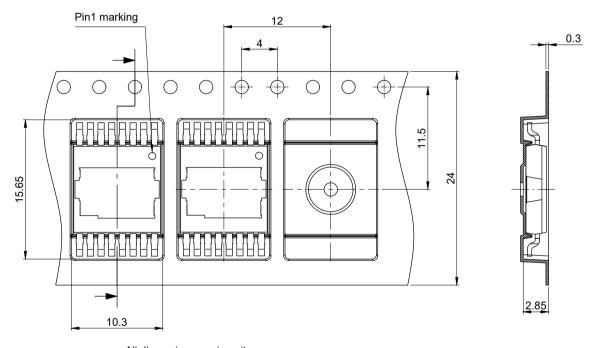


Figure 2 Footprint Drawing PG-HDSOP-16, dimensions in mm





All dimensions are in units mm

The drawing is in compliance with ISO 128-30, Projection Method 1 [

Figure 3 Packaging Variant PG-HDSOP-16, dimensions in mm



8 Appendix A

Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650V G2 Webpage
- IFX CoolSiC CoolSiC™ MOSFET 650V G2 Application Note
- IFX CoolSiC CoolSiC™ MOSFET 650V G2 Simulation Model
- IFX Design tools



Revision History

IMLT65R026M2H

Revision 2024-09-06, Rev. 2.0

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Revision	Date	Subjects (major changes since last revision)
2.0	2024-09-06	Release of final

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